

Doc. ETD 19 (15638)
IS 15638 : Part 1:2006
IEC 61083 -1 : 2021

भारतीय मानक

हाई-वोल्टेज और हाई-करंट परीक्षण में मापन के लिए उपयोग किए जाने वाले उपकरण और सॉफ्टवेयर- भाग
1: आवेग परीक्षण के लिए उपकरणों के लिए आवश्यकताएँ
(पहला पुनरीक्षण)

Indian Standard

Instruments And Software Used For Measurements In High-Voltage And High-Current Tests –
Part 1: Requirements For Instruments For Impulse Tests
(*First Revision*)

ICS 17.220.20; 19.080

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NEW DELHI 110 002

August 2021

Price Group

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Draft Indian Standard

INSTRUMENTS AND SOFTWARE USED FOR MEASUREMENTS IN HIGH-VOLTAGE AND HIGH-CURRENT TESTS – PART 1: REQUIREMENTS FOR INSTRUMENTS FOR IMPULSE TESTS

Last date of receipt of comments is: **26- October -2021**

High Voltage Engineering Sectional Committee, ETD 19

NATIONAL FOREWORD

This draft Indian Standard (Part 1) which is identical with IEC 61083 -1 : 2021 ‘Instruments And Software Used For Measurements In High-Voltage And High-Current Tests – Part 1: Requirements For Instruments For Impulse Tests’ issued by the International Electrotechnical Commission (IEC) will be adopted by the Bureau of Indian Standards on the recommendation of the High Voltage Engineering Sectional Committee and approval of the Electrotechnical Division Council.

This Standard was first Published in 2001 identical to IEC 61083-1 :2021. This revision has been undertaken to align this standard with the latest international practices.

The text of the IEC Standard has been approved as suitable for publication as an Indian Standard without deviations. Certain conventions are, however, not identical to those used in Indian Standards. Attention is particularly drawn to the following:

- a) Wherever the words ‘International Standard’ appears referring to this standard, they should be read as ‘Indian Standard’.
- b) Comma (,) has been used as a decimal marker, while in Indian Standards the current practice is to use a point (.) as the decimal marker.

In this adopted standard, reference appears to International Standards for which Indian Standards also exists. The corresponding Indian Standards, which are to be substituted, are listed below along with their degree of equivalence for the editions indicated:

<i>International Standard</i>	<i>Corresponding Indian Standard</i>	<i>Degree of Equivalence</i>
IEC 60060-1 :2010, High-voltage test techniques – Part 1: General definitions and test requirements	IS 2071 (Part 1) : 2016 High-voltage Test Techniques Part 1 General Definitions and Test Requirements (<i>Third Revision</i>)	Identical with IEC 60060-1 :2010
IEC 60060-2: 2010, High-voltage test techniques – Part 2: Measuring systems	IS/IEC 60060-2 : 2010 High-voltage test techniques – Part 2: Measuring systems	Identical

IEC 62475: 2010, High-current test techniques – Definitions and requirements for test currents and measuring systems	IS 16828 : 2018 High-Current Test Techniques — Definitions and Requirements for Test Currents and Measuring Systems	Identical with IEC 62475: 2010
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The technical committee has reviewed the provisions of the following international standards referred in this adopted standard and decided that they are acceptable for use in conjunction with this standard.

<i>International Standard</i>	<i>Title</i>
ISO/IEC Guide 98-3:2008	Uncertainty of measurement – Part 3: Guide to the expression of uncertainty in measurements (GUM:1995)

Only English language text has been retained while adopting it in this Indian Standard, and as such the page numbers given here are not the same as in the International Standard.

For the purpose of deciding whether a particular requirement of this standard is complied with, the final value, observed or calculated expressing the result of a test, shall be rounded off in accordance with IS 2 : 1960 ‘Rules for rounding off numerical values (revised)’. The number of significant places retained in the rounded off value should be the same as that of the specified value in this standard.

Note: The technical content of the document is not available on website. For details, please refer the corresponding IEC 61083 -1 : 2021 or kindly contact:

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